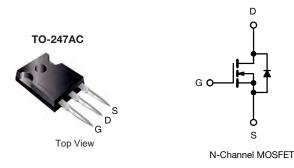


24NM65N-VB TO247 Datasheet

N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY					
V_{DS} (V) at T_J max.	650				
R _{DS(on)} (Ω) at 25 °C	$V_{GS} = 10 V$	0.19			
Q _g max. (nC)	106				
Q _{gs} (nC)	14				
Q _{gd} (nC)	33				
Configuration	Single				



FEATURES

- Reduced t_{rr}, Q_{rr}, and I_{RRM}
- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q_{rr}
- Ultra low gate charge (Q_q)

Avalanche energy rated (UIS)

APPLICATIONS

- Telecommunications
 - Server and telecom power supplies
- Lighting
 - High-intensity discharge (HID)
- Fluorescent ballast lighting
- Consumer and computing - ATX power supplies
- Industrial
 - Welding
 - Battery chargers
- Renewable energy
- Solar (PV inverters)
- Switch mode power supplies (SMPS)

= 25 °C, unl	less otherwis	se noted)			
PARAMETER			LIMIT	UNIT	
Drain-Source Voltage			650	V	
Gate-Source Voltage			± 30	V	
V at 10 V	T _C = 25 °C	- I _D	20		
V _{GS} at 10 V	T _C = 100 °C		13	А	
Pulsed Drain Current ^a			53		
Linear Derating Factor			1.7	W/°C	
Single Pulse Avalanche Energy ^b			367	mJ	
Maximum Power Dissipation			208	W	
Operating Junction and Storage Temperature Range			-55 to +150	°C	
T _J = 125 °C		d\//dt	37	V/ns	
Reverse Diode dV/dt ^d			31	v/ns	
for 10 s			300	°C	
	V _{GS} at 10 V e T _J = [−]	$V_{GS} \text{ at } 10 \text{ V} \qquad T_{C} = 25 \text{ °C}}{T_{C} = 100 \text{ °C}}$ e $T_{J} = 125 \text{ °C}$	I_{DM} E_{AS} P_{D} $e T_{J}, T_{stg}$ $T_{J} = 125 \ ^{\circ}C dV/dt$	$\begin{tabular}{ c c c c c c } \hline SYMBOL & LIMIT \\ \hline V_{DS} & 650 \\ \hline V_{GS} & \pm 30 \\ \hline V_{GS} & \pm 30 \\ \hline V_{GS} & \pm 10 \ V & \hline T_C = 25 \ ^{\circ}C & I_D & 20 \\ \hline T_C = 100 \ ^{\circ}C & I_D & 13 \\ \hline & I_DM & 53 \\ \hline & I_{DM} & 53 \\ \hline & $I_{T,T}$ & $I_{T,T}$ \\ \hline & E_{AS} & 367 \\ \hline & P_D & 208 \\ \hline & T_J, T_{stg} & -55 to +150$ \\ \hline & $T_J = 125 \ ^{\circ}C$ & dV/dt & 31 \\ \hline \end{tabular}$	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 5.1 A.

c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.



THERMAL RESISTANCE RAT	NGS							
PARAMETER	SYMBOL	TYP. MAX.			UNIT			
Maximum Junction-to-Ambient	R _{thJA}	- 62			°C/W			
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.5						
SPECIFICATIONS ($T_J = 25 \ ^{\circ}C$, u	unless otherw	ise noted)						
PARAMETER	SYMBOL		T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
Static					1		1	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D =	250 µA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I _D = 1 mA	-	0.67	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}		= V _{GS} , I _D =		2	-	4	V
		$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA	
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 30 V		-	-	± 1	μA
	1	V _{DS} =	= 520 V, V _C	_{as} = 0 V	-	-	1	
Zero Gate Voltage Drain Current	b Gate Voltage Drain Current I_{DSS} $V_{DS} = 520 V, V_{GS} = 0 V, T_J = 125$		V, T _J = 125 °C	-	-	500	μA	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I	_D = 11 A	-	0.19	-	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 30 V, I _D	= 11 A	-	7.0	-	S
Dynamic	•							•
Input Capacitance	C _{iss}		V _{GS} = 0 V, V _{DS} = 100 V,		-	2322	-	
Output Capacitance	C _{oss}				-	105	-	
Reverse Transfer Capacitance	C _{rss}	f = 1 MHz		-	4	-	pF	
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	$V_{DS} = 0$ V to 520 V, $V_{GS} = 0$ V		-	84	-		
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	293	-		
Total Gate Charge	Qg		V _{GS} = 10 V I _D = 11 A, V _{DS} = 520 V		-	71	106	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V			-	14	-	
Gate-Drain Charge	Q _{gd}				-	33	-	
Turn-On Delay Time	t _{d(on)}		$V_{DD} = 520 \text{ V}, \text{ I}_{D} = 11 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{g} = 9.1 \Omega$		-	22	44	-
Rise Time	t _r	V _{DD} =			-	34	68	
Turn-Off Delay Time	t _{d(off)}	V _{GS} :			-	68	102	ns
Fall Time	t _f]		-	42	84]	
Gate Input Resistance	R _g	f = 1 MHz, open drain		-	0.78	-	Ω	
Drain-Source Body Diode Characteristi	cs							
Continuous Source-Drain Diode Current	I _S	MOSFET sym showing the	MOSFET symbol showing the		-	-	21	_
Pulsed Diode Forward Current	I _{SM}	integral reverse p - n junction diode			-	-	53	A
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 11 A, V _{GS} = 0 V		-	0.9	1.2	V	
Reverse Recovery Time	t _{rr}		······································		-	160	-	ns
Reverse Recovery Charge	Q _{rr}	T _J = 25 °C, I _F = I _S = 11 A, dl/dt = 100 A/μs, V _R = 25 V		-	1.2	-	μC	
Reverse Recovery Current	I _{RRM}			-	14	-	A	
· · · ·				1	i	1	L	

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

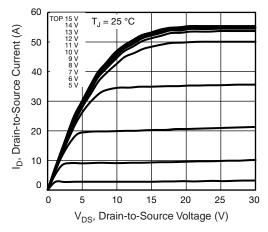


Fig. 1 - Typical Output Characteristics



Fig. 2 - Typical Output Characteristics

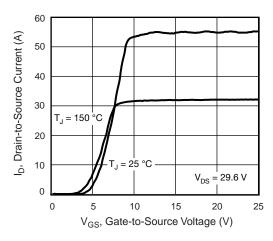


Fig. 3 - Typical Transfer Characteristics

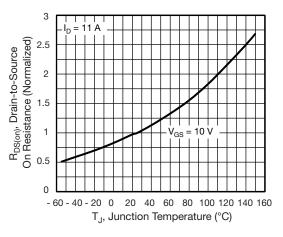


Fig. 4 - Normalized On-Resistance vs. Temperature

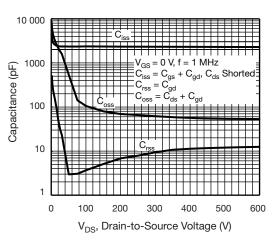


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

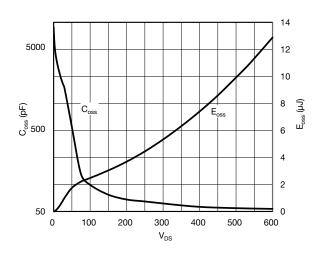


Fig. 6 - C_{oss} and E_{oss} vs. V_{DS}

24NM65N-VB TO247



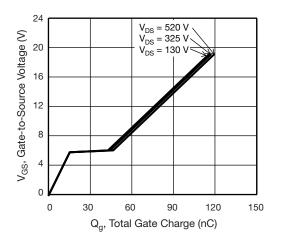


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

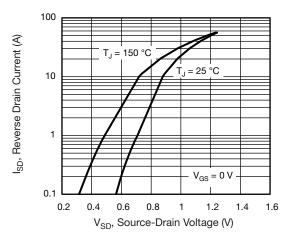


Fig. 8 - Typical Source-Drain Diode Forward Voltage

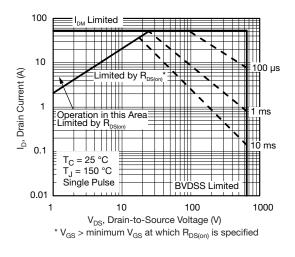


Fig. 9 - Maximum Safe Operating Area

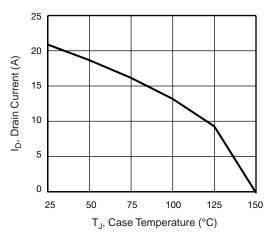


Fig. 10 - Maximum Drain Current vs. Case Temperature



Fig. 11 - Temperature vs. Drain-to-Source Voltage



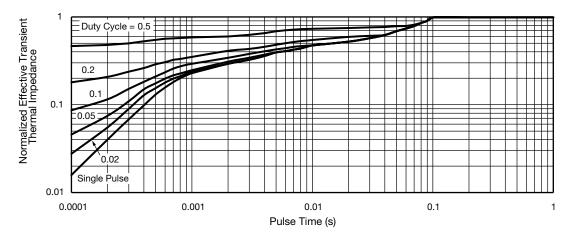


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case



Fig. 13 - Switching Time Test Circuit



Fig. 14 - Switching Time Waveforms

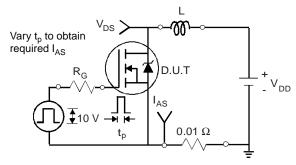


Fig. 15 - Unclamped Inductive Test Circuit

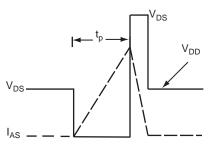


Fig. 16 - Unclamped Inductive Waveforms

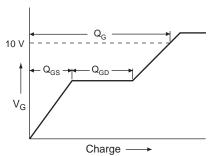
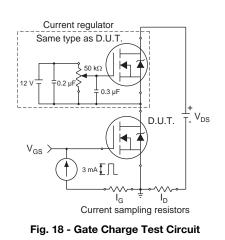
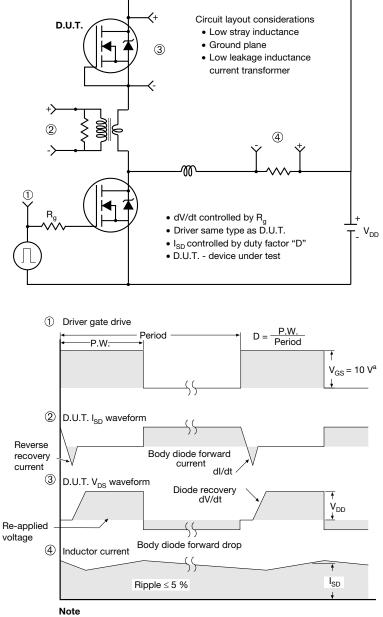


Fig. 17 - Basic Gate Charge Waveform





Peak Diode Recovery dV/dt Test Circuit



a. $V_{GS} = 5$ V for logic level devices

Fig. 19 - For N-Channel



Disclaimer

All products due to improve reliability, function or design or for other reasons, product specifications and data are subject to change without notice.

Taiwan VBsemi Electronics Co., Ltd., branches, agents, employees, and all persons acting on its or their representatives (collectively, the "Taiwan VBsemi"), assumes no responsibility for any errors, inaccuracies or incomplete data contained in the table or any other any disclosure of any information related to the product.(www.VBsemi.com)

Taiwan VBsemi makes no guarantee, representation or warranty on the product for any particular purpose of any goods or continuous production. To the maximum extent permitted by applicable law on Taiwan VBsemi relinquished: (1) any application and all liability arising out of or use of any products; (2) any and all liability, including but not limited to special, consequential damages or incidental; (3) any and all implied warranties, including a particular purpose, non-infringement and merchantability guarantee.

Statement on certain types of applications are based on knowledge of the product is often used in a typical application of the general product VBsemi Taiwan demand that the Taiwan VBsemi of. Statement on whether the product is suitable for a particular application is non-binding. It is the customer's responsibility to verify specific product features in the products described in the specification is appropriate for use in a particular application. Parameter data sheets and technical specifications can be provided may vary depending on the application and performance over time. All operating parameters, including typical parameters must be made by customer's technical experts validated for each customer application. Product specifications do not expand or modify Taiwan VBsemi purchasing terms and conditions, including but not limited to warranty herein.

Unless expressly stated in writing, Taiwan VBsemi products are not intended for use in medical, life saving, or life sustaining applications or any other application. Wherein VBsemi product failure could lead to personal injury or death, use or sale of products used in Taiwan VBsemi such applications using client did not express their own risk. Contact your authorized Taiwan VBsemi people who are related to product design applications and other terms and conditions in writing.

The information provided in this document and the company's products without a license, express or implied, by estoppel or otherwise, to any intellectual property rights granted to the VBsemi act or document. Product names and trademarks referred to herein are trademarks of their respective representatives will be all.

Material Category Policy

Taiwan VBsemi Electronics Co., Ltd., hereby certify that all of the products are determined to be RoHS compliant and meets the definition of restrictions under Directive of the European Parliament 2011/65 / EU, 2011 Nian. 6. 8 Ri Yue restrict the use of certain hazardous substances in electrical and electronic equipment (EEE) - modification, unless otherwise specified as inconsistent.(www.VBsemi.com)

Please note that some documents may still refer to Taiwan VBsemi RoHS Directive 2002/95 / EC. We confirm that all products identified as consistent with the Directive 2002/95 / EC European Directive 2011/65 /.

Taiwan VBsemi Electronics Co., Ltd. hereby certify that all of its products comply identified as halogen-free halogen-free standards required by the JEDEC JS709A. Please note that some Taiwanese VBsemi documents still refer to the definition of IEC 61249-2-21, and we are sure that all products conform to confirm compliance with IEC 61249-2-21 standard level JS709A.